Power MOSFET

40 V, 2.3 m Ω , 185 A, Single N-Channel

Features

- Small Footprint (5x6 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- These are Pb-Free Devices*

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise noted)

| Parameter | | | Symbol | Value | Unit |
|---|---------------------|----------------------------|-----------------------------------|-----------------|------|
| Drain-to-Source Voltage | | | V_{DSS} | 40 | V |
| Gate-to-Source Voltage | | | V _{GS} | ± 20 | V |
| Continuous Drain Current R _{Ψ,I-mh} (Notes 1, | Steady State | T _{mb} = 25°C | I _D | 185 | Α |
| 2, 3, 4) | | T _{mb} = 100°C | | 131 | |
| Power Dissipation | | T _{mb} = 25°C | P _D | 158 | W |
| R _{ΨJ-mb} (Notes 1, 2, 3) | | T _{mb} = 100°C | | 79 | |
| Continuous Drain Cur- | | T _A = 25°C | I _D | 29 | Α |
| rent R _{0JA} (Notes 1, 3, 4) | Steady State | T _A = 100°C | | 20 | |
| Power Dissipation | | T _A = 25°C | P_{D} | 3.8 | W |
| R _{θJA} (Notes 1 & 3) | | T _A = 100°C | | 1.9 | |
| Pulsed Drain Current | T _A = 25 | °C, t _p = 10 μs | I _{DM} | 1012 | Α |
| Operating Junction and Storage Temperature | | | T _J , T _{stg} | –55 to + 175 | °C |
| Source Current (Body Diode) | | | Is | 185 | Α |
| Single Pulse Drain-to-Source Avalanche Energy (T _J = 25°C, V _{GS} = 10 V, I _{L(pk)} = 85 A, L = 0.1 mH, R _G = 25 Ω) | | | E _{AS} | 361 | mJ |
| Lead Temperature for Soldering Purposes (1/8" from case for 10 s) | | | TL | 260 | °C |

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

THERMAL RESISTANCE MAXIMUM RATINGS

| Parameter | Symbol | Value | Unit |
|---|-----------------|-------|------|
| Junction-to-Mounting Board (top) - Steady State (Notes 2, 3) | $R_{\Psi J-mb}$ | 1.0 | °C/W |
| Junction-to-Ambient - Steady State (Note 3) | $R_{\theta JA}$ | 39 | |

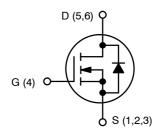
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Psi (Ψ) is used as required per JESD51-12 for packages in which substantially less than 100% of the heat flows to single case surface.
- 3. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- 4. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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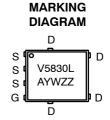
http://onsemi.com

| V _{(BR)DSS} | R _{DS(ON)} MAX | I _D MAX |
|----------------------|-------------------------|--------------------|
| 40 V | 2.3 mΩ @ 10 V | 10F A |
| 40 V | 3.6 mΩ @ 4.5 V | 185 A |



N-CHANNEL MOSFET





A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

| Device | Package | Shipping [†] |
|----------------|---------------------|-----------------------|
| NVMFS5830NLT1G | SO-8FL (Pb-Free) | 1500 / Tape & Reel |
| NVMFS5830NLT3G | SO-8FL (Pb-Free) | 5000 / Tape & Reel |

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

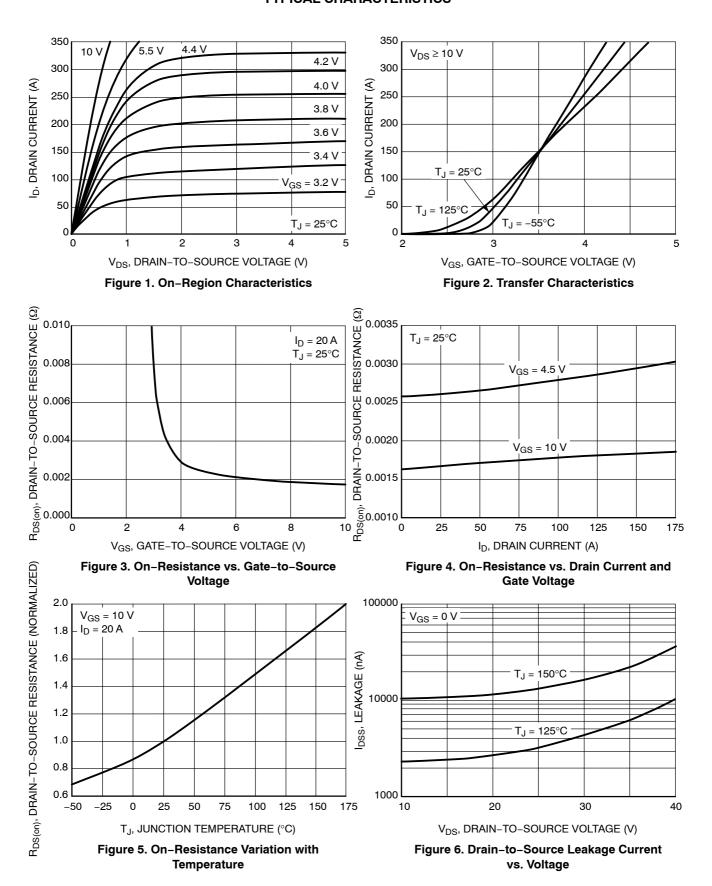
^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

| Parameter | Symbol | Test Condition | | Min | Тур | Max | Unit |
|--|-------------------------------------|--|------------------------|-----|------|------|-------|
| OFF CHARACTERISTICS | | | | | | 1 | • |
| Drain-to-Source Breakdown Voltage | V _{(BR)DSS} | $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$ | | 40 | | | V |
| Drain-to-Source Breakdown Voltage Temperature Coefficient | V _{(BR)DSS} / | | | | 32 | | mV/°C |
| Zero Gate Voltage Drain Current | I _{DSS} | I _{DSS} V _{GS} = 0 V, V _{DS} = 40 V | | | | 1 | |
| | | $V_{DS} = 40 \text{ V}$ | T _J = 125°C | | | 100 | μΑ |
| Gate-to-Source Leakage Current | I _{GSS} | $V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$ | | | | ±100 | nA |
| ON CHARACTERISTICS (Note 5) | | | | | • | • | • |
| Gate Threshold Voltage | V _{GS(TH)} | $V_{GS} = V_{DS}, I_D =$ | = 250 μΑ | 1.4 | | 2.4 | V |
| Negative Threshold Temperature Coefficient | V _{GS(TH)} /T _J | | | | 7.2 | | mV/°C |
| Drain-to-Source On Resistance | R _{DS(on)} | V _{GS} = 10 V | I _D = 20 A | | 1.7 | 2.3 | _ |
| | | V _{GS} = 4.5 V | I _D = 20 A | | 2.6 | 3.6 | mΩ |
| Forward Transconductance | 9FS | $V_{DS} = 5 \text{ V}, I_{D}$ | = 10 A | | 38 | | S |
| CHARGES, CAPACITANCES & GATE RESIS | TANCE | | | | • | • | • |
| Input Capacitance | C _{ISS} | | | | 5880 | | |
| Output Capacitance | C _{OSS} | $V_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}, V_{DS} = 25 \text{ V}$ $V_{GS} = 4.5 \text{ V}, V_{DS} = 32 \text{ V}; I_{D} = 60 \text{ A}$ | | | 750 | | pF |
| Reverse Transfer Capacitance | C _{RSS} | | | | 500 | | |
| Total Gate Charge | Q _{G(TOT)} | | | | 58 | | nC |
| Total Gate Charge | Q _{G(TOT)} | V _{GS} = 10 V, V _{DS} = 32 V; I _D = 60 A | | | 113 | | nC |
| Threshold Gate Charge | Q _{G(TH)} | V _{GS} = 4.5 V, V _{DS} = 32 V; I _D = 60 A | | | 5.5 | | |
| Gate-to-Source Charge | Q _{GS} | | | | 19.5 | | nC |
| Gate-to-Drain Charge | Q_{GD} | | | | 32 | | |
| Plateau Voltage | V_{GP} | | | | 3.6 | | V |
| SWITCHING CHARACTERISTICS (Note 6) | | | | | | • | • |
| Turn-On Delay Time | t _{d(ON)} | | | | 22 | | |
| Rise Time | t _r | $V_{GS} = 4.5 \text{ V}, V_{DS}$ | s = 20 V, | | 32 | | |
| Turn-Off Delay Time | t _{d(OFF)} | $I_D = 10 \text{ A}, R_G = 2.5 \Omega$ | | | 40 | | ns |
| Fall Time | t _f | | | | 27 | | |
| DRAIN-SOURCE DIODE CHARACTERISTIC | s | | | | | • | • |
| Forward Diode Voltage | V _{SD} | V _{GS} = 0 V, | T _J = 25°C | | 0.74 | 1.0 | ., |
| | | I _S = 10 A | T _J = 125°C | | 0.58 | | \ \ |
| Reverse Recovery Time | t _{RR} | V _{GS} = 0 V, dIS/dt = 100 A/μs, I _S = 60 A | | | 41 | | |
| Charge Time | ta | | | | 19 | | ns |
| Discharge Time | t _b | | | | 19 | | 1 |
| Reverse Recovery Charge | Q _{RR} | | | | 33 | | nC |

^{5.} Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS



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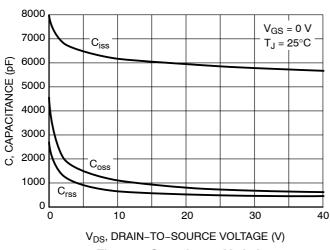


Figure 7. Capacitance Variation

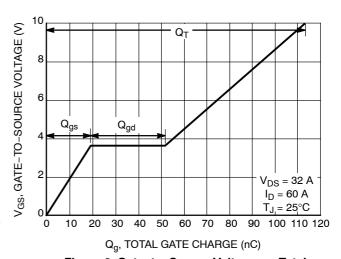


Figure 8. Gate-to-Source Voltage vs. Total Charge

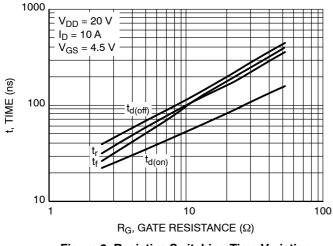


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

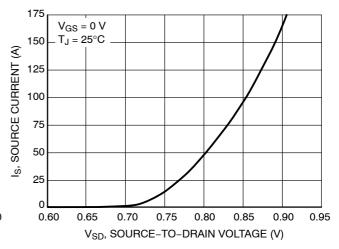


Figure 10. Diode Forward Voltage vs. Current

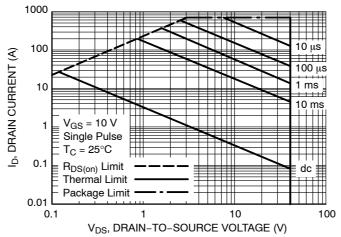


Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS

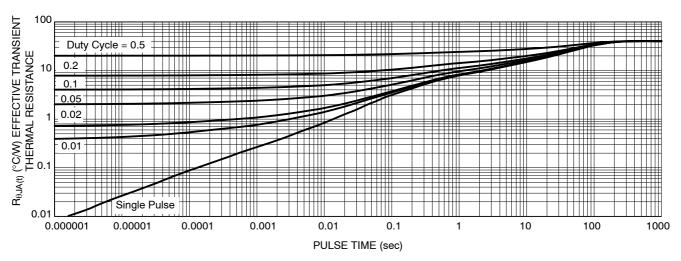
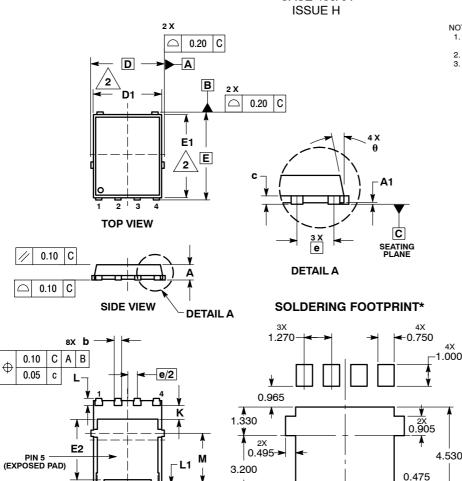


Figure 12. Thermal Response

PACKAGE DIMENSIONS





NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETER. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE

| | MILLIMETERS | | | | |
|-----|-------------|----------|------|--|--|
| DIM | MIN | NOM | MAX | | |
| Α | 0.90 | 1.00 | 1.10 | | |
| A1 | 0.00 | | 0.05 | | |
| b | 0.33 | 0.41 | 0.51 | | |
| С | 0.23 | 0.28 | 0.33 | | |
| D | | 5.15 BSC | ; | | |
| D1 | 4.70 | 4.90 | 5.10 | | |
| D2 | 3.80 | 4.00 | 4.20 | | |
| E | 6.15 BSC | | | | |
| E1 | 5.70 | 5.90 | 6.10 | | |
| E2 | 3.45 | 3.65 | 3.85 | | |
| е | | 1.27 BSC | | | |
| G | 0.51 | 0.61 | 0.71 | | |
| K | 1.20 | 1.35 | 1.50 | | |
| L | 0.51 | 0.61 | 0.71 | | |
| L1 | 0.05 | 0.17 | 0.20 | | |
| М | 3.00 | 3.40 | 3.80 | | |
| θ | 0 ° | | 12 ° | | |

.000

- STYLE 1: PIN 1. SOURCE 2. SOURCE 3. SOURCE

 - GATE DRAIN

 - DRAIN

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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